SCAS414L - NOVEMBER 1992 - REVISED APRIL 1999

- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V_{OLP} (Output Ground Bounce)
 <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot) >2 V at V_{CC} = 3.3 V, T_A = 25°C
- Power Off Disables Outputs, Permitting Live Insertion
- Supports Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V_{CC})
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Shrink
 Small-Outline (DB), Plastic Small-Outline
 (DW), and Thin Shrink Small-Outline (PW)
 Packages

DB, DW, OR PW PACKAGE (TOP VIEW)

1OE [1A1 [2Y4 [1A2 [2Y3 [1A3 [2Y2 [1A4 [2Y1 [2 3 4 5	20 19 18 17 16 15 14 13 12	V _{CC} 2OE 1Y1 2A4 1Y2 2A3 1Y3 2A2
2Y1 [GND [12 11	1Y4 2A1

description

This octal buffer/line driver is operational at 1.5-V to 3.6-V V_{CC}, but designed specifically for 1.65-V to 3.6-V V_{CC} operation.

The SN74LVC244A is organized as two 4-bit line drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVC244A is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each buffer)

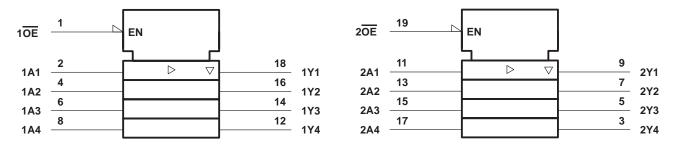
INPUTS		OUTPUT
OE	Α	Υ
	Н	Н
L	L	W L
C CHIA	Χ	Z

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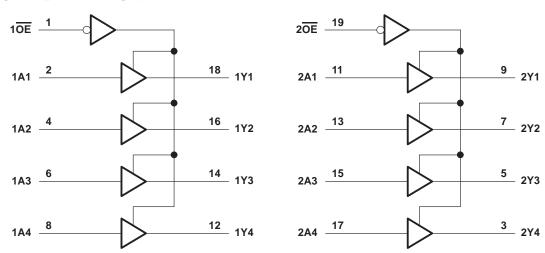


logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	–0.5 V to 6.5 V
Input voltage range, V _I (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, V _O	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	\cdot . -0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The value of $V_{\hbox{CC}}$ is provided in the recommended operating conditions table.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vac	Supply voltage	Operating	1.65	3.6	V
Vcc	Supply voltage	Data retention only	1.5		V
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.5		V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		$0.35 \times V_{CC}$	
VIL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	0.7	V
		V _{CC} = 2.7 V to 3.6 V		0.8	
٧ _I	Input voltage		0	5.5	V
\/-	Output voltage		0	Vcc	V
Vo	Output voltage	3 state	0	5.5	
		V _{CC} = 1.65 V		-4	
l ,	High level cutout current	V _{CC} = 2.3 V		-8	A
ЮН	High-level output current	V _{CC} = 2.7 V		-12	mA
		V _{CC} = 3 V		-24	
		V _{CC} = 1.65 V		4	
	Low lovel output current	V _{CC} = 2.3 V		8	mA
IOL	Low-level output current	V _{CC} = 2.7 V		12	
		VCC = 3 V		24	
TA	Operating free-air temperature		-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

SN74LVC244A **OCTAL BUFFER/DRIVER** WITH 3-STATE OUTPUTS SCAS414L – NOVEMBER 1992 – REVISED APRIL 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	ONDITIONS	Vcc	MIN	TYP [†]	MAX	UNIT
	I _{OH} = -100 μA	1.65 V to 3.6 V	V _{CC} -0.	2			
	I _{OH} = -4 mA		1.65 V	1.2			
Vari	I _{OH} = -8 mA	$I_{OH} = -8 \text{ mA}$					V
VOH	I _{OH} = -12 mA	1 40 1					V
	IOH = -12 IIIA	3 V		2.4			
	I _{OH} = -24 mA		3 V	2.2			
	I _{OL} = 100 μA		1.65 V to 3.6 V			0.2	
	I _{OL} = 4 mA	1.65 V			0.45	V	
V _{OL}	I _{OL} = 8 mA	2.3 V			0.7		
	I _{OL} = 12 mA	2.7 V			0.4		
	I _{OL} = 24 mA		3 V			0.55	
lį	V _I = 0 to 5.5 V		3.6 V			±5	μΑ
loff	V _I or V _O = 5.5 V		0			±10	μΑ
loz	V _O = 0 to 5.5 V		3.6 V			±10	μΑ
	$V_I = V_{CC}$ or GND			10		10	
lcc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\ddagger}$	IO = 0	3.6 V			μΑ	
ΔlCC	One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500	μΑ
Ci	$V_I = V_{CC}$ or GND		3.3 V		4		pF
Co	$V_O = V_{CC}$ or GND		3.3 V		5.5		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. ‡ This applies in the disabled state only.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 4)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.5 V	V _{CC} = 1.8 V	V _{CC} =		VCC =	2.7 V	V _{CC} =	3.3 V 3 V	UNIT	
(INPUT)	(1141 01)	(0011 01)	TYP	TYP	MIN	MAX	MIN	MAX	MIN	MAX			
	^t pd	А	Υ	5.75	12	1	7.9		6.9	1.5	5.9	ns	
	t _{en}	ŌĒ	Υ	6.59	13.1	1	9.6		8.6	1.5	7.6	ns	
	^t dis	ŌĒ	Y	5.7	14.6	1	7.8		6.8	1.5	6.5	ns	

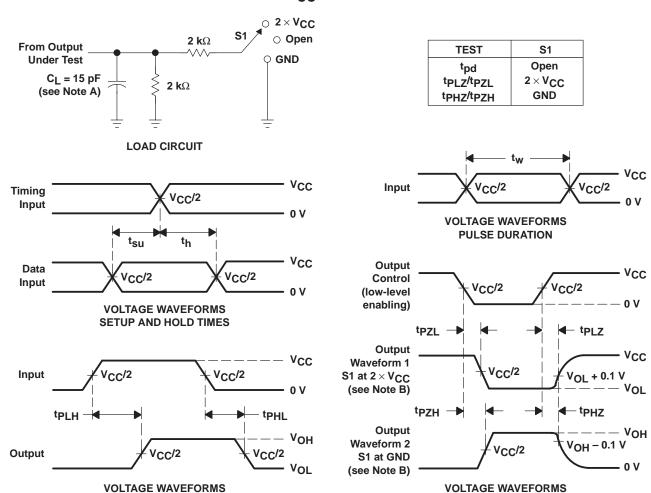
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER		TEST	V _{CC} = 1.8 V	$V_{CC} = 2.5 V$	$V_{CC} = 3.3 \text{ V}$	UNIT
	FARAMETER	CONDITI		TYP	TYP	TYP	ONIT
Const	Power dissipation capacitance Outputs enabled		f = 10 MHz	43	43	44	ρF
C _{pd}	per buffer/driver	Outputs disabled	T = TO WIHZ	1	1	2	PΓ



ENABLE AND DISABLE TIMES

PARAMETER MEASUREMENT INFORMATION V_{CC} = 1.5 V



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tpLz and tpHz are the same as tdis.

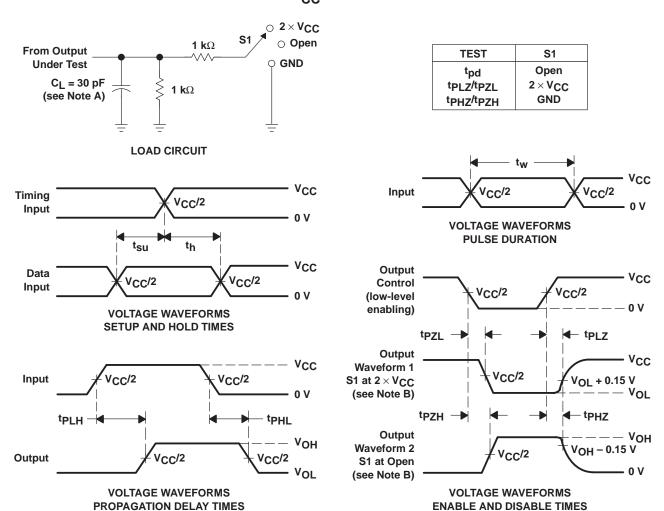
PROPAGATION DELAY TIMES

- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V}$



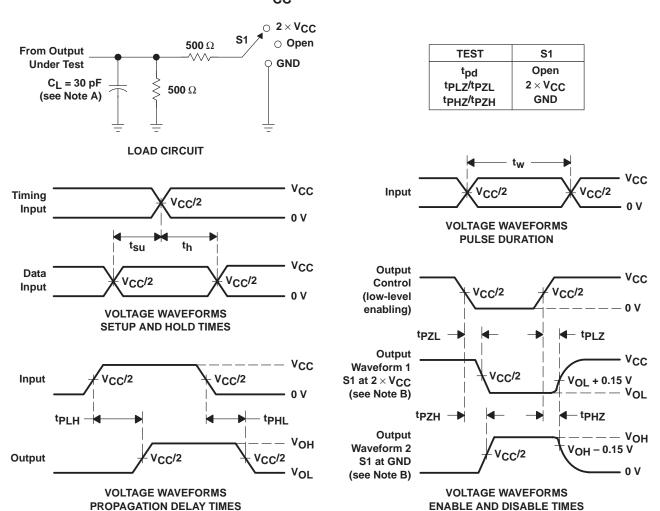
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



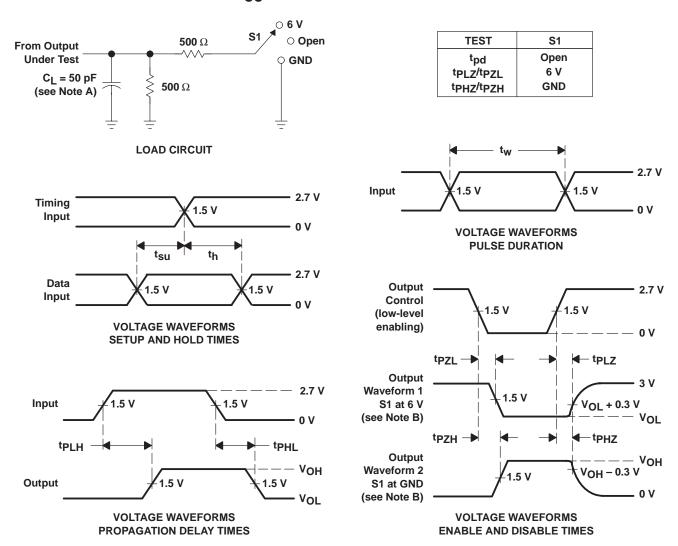
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpZL and tpZH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7 \text{ V}$ AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 4. Load Circuit and Voltage Waveforms



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